

# ANNOUNCEMENT

---

September 14, 1999  
**FOR IMMEDIATE RELEASE**

*APPLY X-RAY DIFFRACTION TO CHARACTERIZE MATERIALS ESSENTIAL FOR  
APPLIED AND BASIC RESEARCH, PRODUCT DEVELOPMENT, PROCESS  
CONTROL, TROUBLESHOOTING, PROBLEM SOLVING, AND QUALITY ASSURANCE*

Marcel Dekker, Inc. proudly announces the publication of **INDUSTRIAL APPLICATIONS OF X-RAY DIFFRACTION**.

**INDUSTRIAL APPLICATIONS OF X-RAY DIFFRACTION** is edited by Frank H. Chung, The Sherwin-Williams Company, Chicago, Illinois, and Deane K. Smith, The Pennsylvania State University, University Park, Pennsylvania.

**INDUSTRIAL APPLICATIONS OF X-RAY DIFFRACTION (ISBN: 0-8247-1992-1 / Publication Date: September, 1999)** contains 1024 pages, 44 chapters, 49 contributors, 1776 references, 303 drawings, 292 equations, 143 photographs, and 119 tables. **Price: \$245.00.**

To request a *Review Copy* of **INDUSTRIAL APPLICATIONS OF X-RAY DIFFRACTION**, contact:

Mrs. Eridiana Perez  
Marcel Dekker, Inc.  
270 Madison Avenue  
New York, NY 10016-0602  
Tel: 212-696-9000 Fax: 212-685-4540  
www.dekker.com